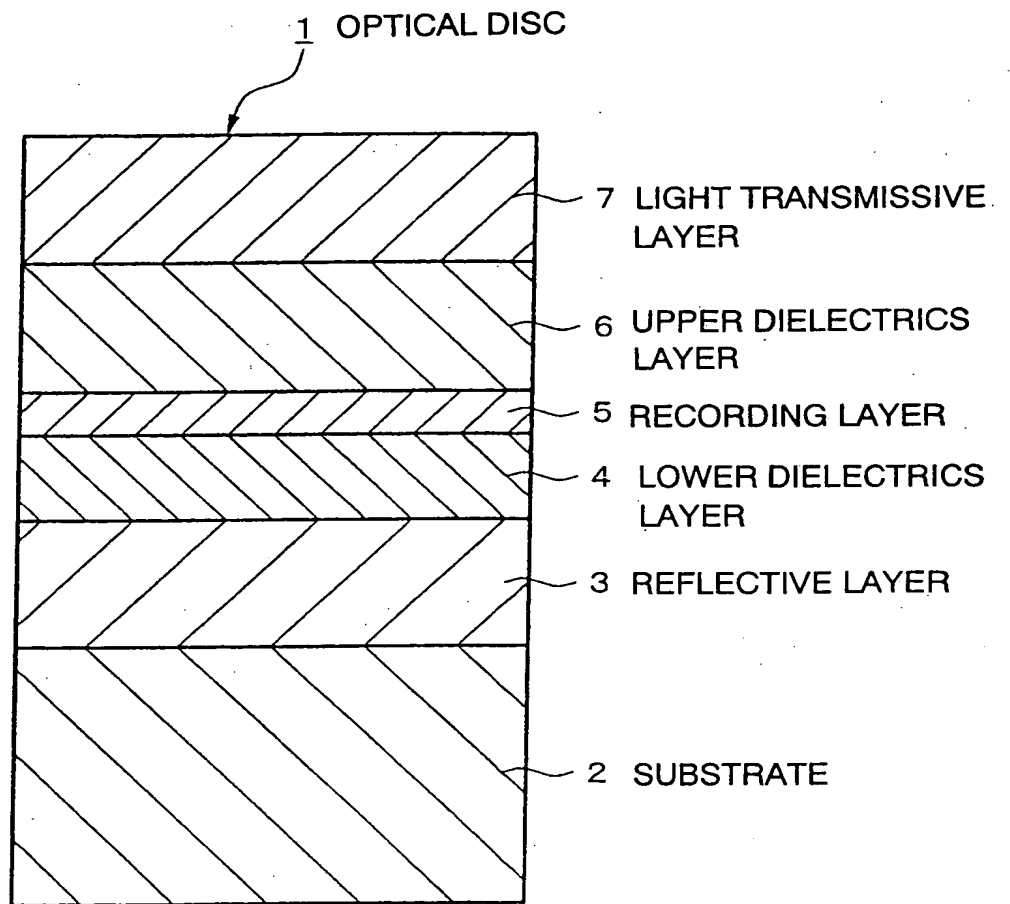
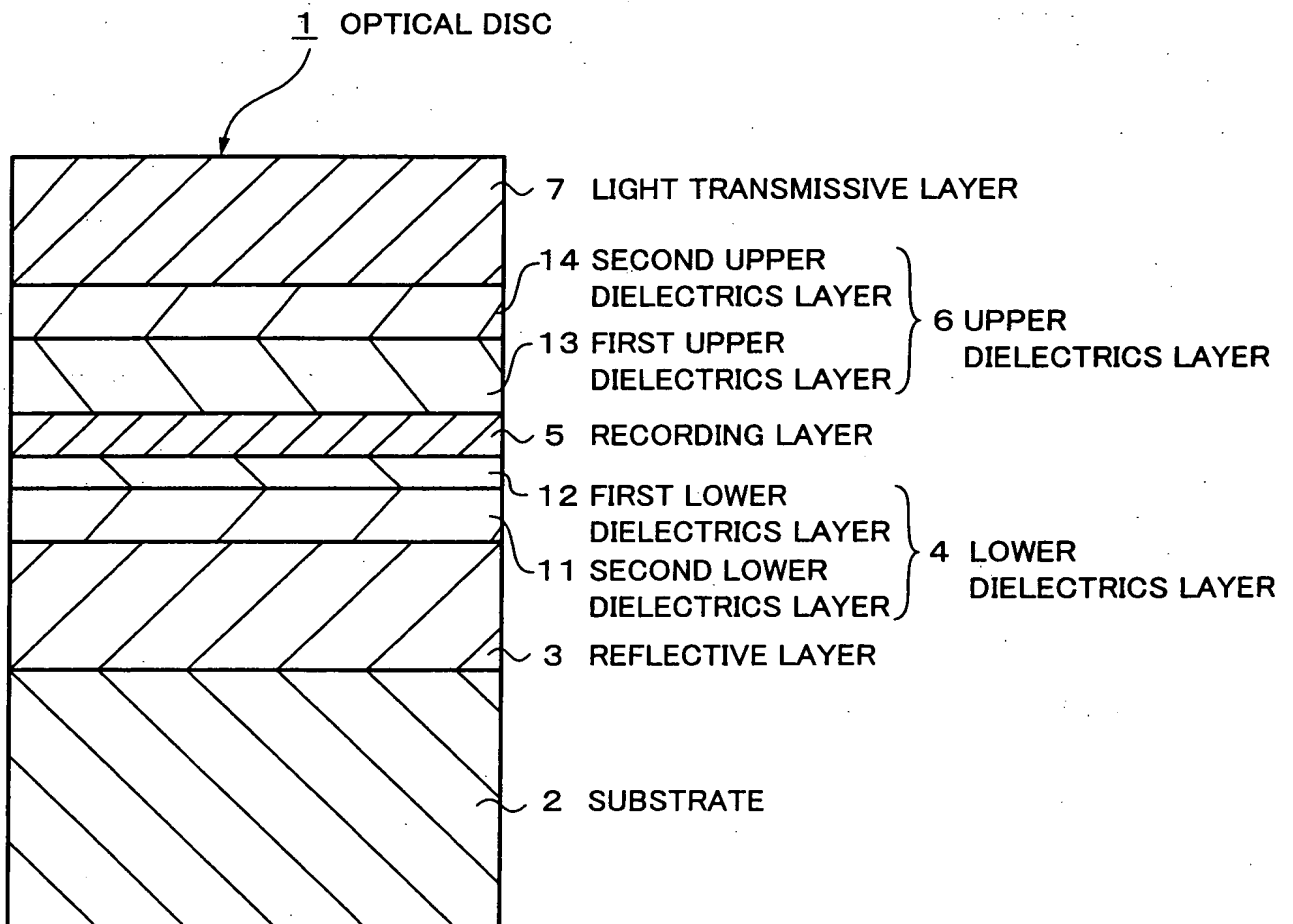
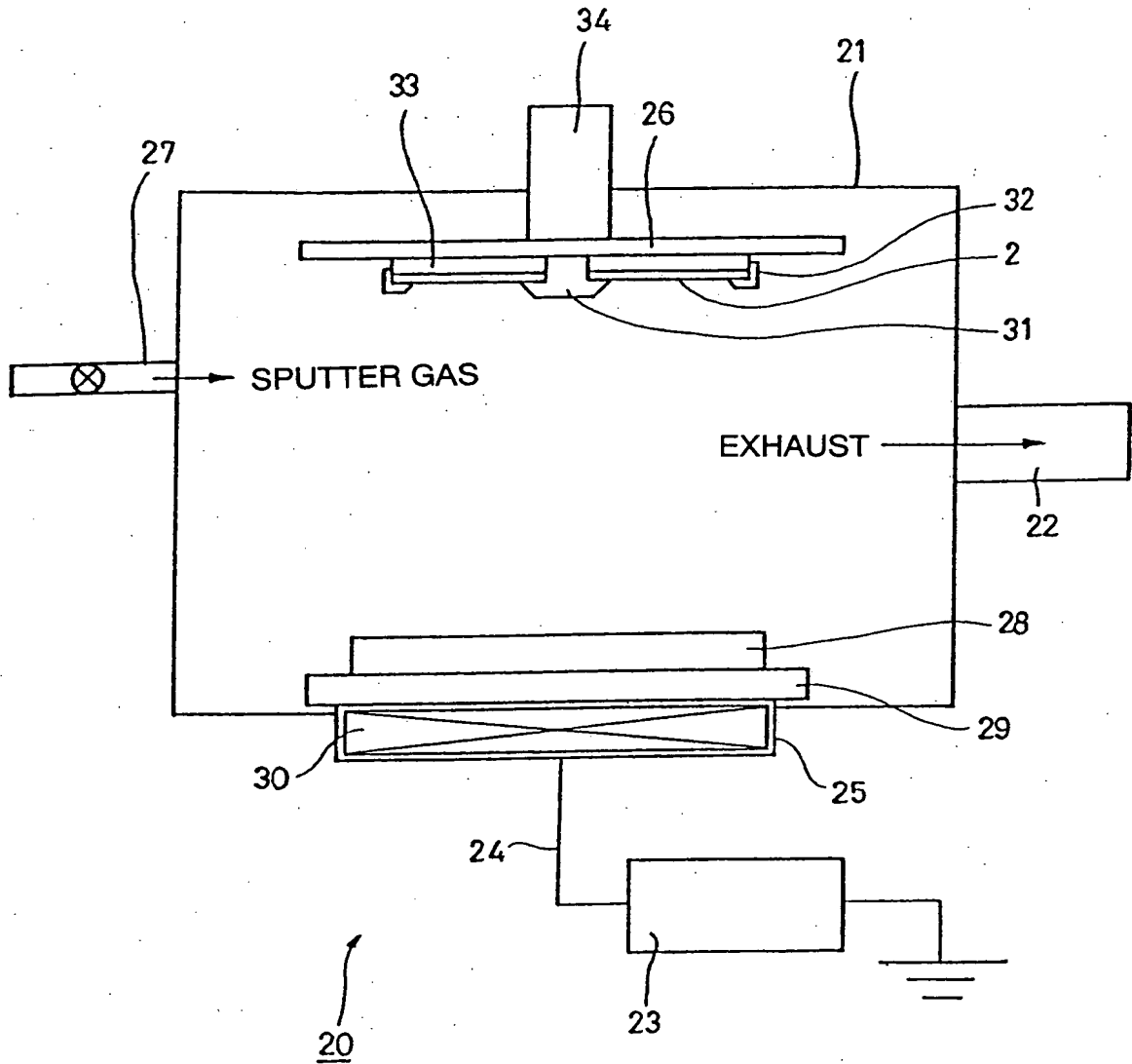


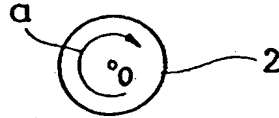
**Fig. 1**



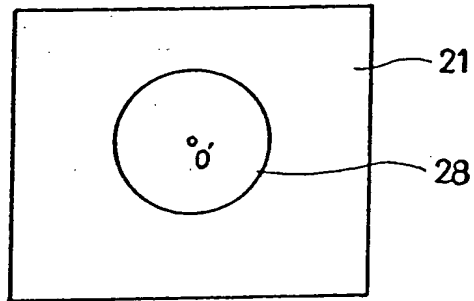
**Fig. 2**

**Fig. 3**

**Fig. 4A**



**Fig. 4B**



**Fig. 4C**

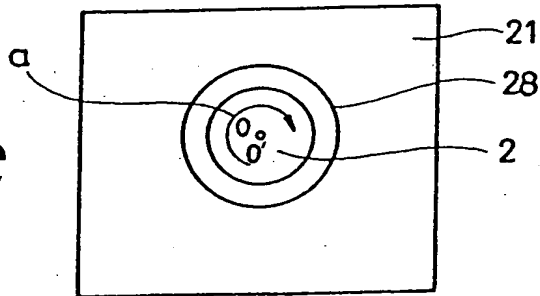


Fig. 5

	REFLECTIVE LAYER [nm]	SECOND LOWER DIELECTRICS LAYER [nm]	FIRST LOWER DIELECTRICS LAYER [nm]	RECORDING LAYER [nm]	FIRST UPPER DIELECTRICS LAYER [nm]	SECOND UPPER DIELECTRICS LAYER [nm]	COMPOSITION OF REFLECTIVE FILM
EXAMPLE 1	60	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 2	80	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 3	120	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 4	140	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 5	100	4	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 6	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 7	100	14	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 8	100	18	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 9	100	8	4	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 10	100	8	10	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 11	100	8	12	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 12	100	8	6	6	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 13	100	8	6	8	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 14	100	8	6	16	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 15	100	8	6	18	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 16	100	8	6	10	4	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 17	100	8	6	10	10	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 18	100	8	6	10	12	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 19	100	8	6	10	8	30	Ag0.4at%Nd0.6at%Cu
EXAMPLE 20	100	8	6	10	8	36	Ag0.4at%Nd0.6at%Cu
EXAMPLE 21	100	8	6	10	8	46	Ag0.4at%Nd0.6at%Cu
EXAMPLE 22	100	8	6	10	8	50	Ag0.4at%Nd0.6at%Cu
COMPARATIVE EXAMPLE	100	18	0	10	0	50	Ag0.4at%Nd0.6at%Cu
EXAMPLE 23	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 24	100	8	6	10	8	40	Ag0.7at%Nd0.9at%Cu

Fig. 6

	REFLECTIVE LAYER [nm]	SECOND LOWER DIELECTRICS LAYER [nm]	FIRST LOWER DIELECTRICS LAYER [nm]	RECORDING LAYER [nm]	FIRST UPPER DIELECTRICS LAYER [nm]	SECOND UPPER DIELECTRICS LAYER [nm]	COMPOSITION OF REFLECTIVE FILM
EXAMPLE 25	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 26	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 27	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 28	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 29	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 30	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 31	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 32	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 33	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 34	100	10	5	12	6	42	Ag0.4at%Nd0.6at%Cu
EXAMPLE 35	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 36	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 37	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 38	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 39	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 40	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 41	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 42	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 43	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu
EXAMPLE 44	100	8	6	10	8	40	Ag0.4at%Nd0.6at%Cu



Fig. 8

	Ge [at%]	Sb/Te	1 ×		1 ×	
			JITTER < 9 %	RECORDING SENSITIVITY < 5. 2mW	JITTER AFTER STORAGE < 9 %	
EXAMPLE 25	4	3. 2	×	○	○	○
EXAMPLE 26	4	3. 4	○	○	○	○
EXAMPLE 27	4	3. 7	○	○	○	○
EXAMPLE 28	4	4	○	○	○	○
EXAMPLE 29	4	4. 4	○	×	○	○
EXAMPLE 30	4	4. 7	○	×	○	○
EXAMPLE 31	0	3. 6	○	○	×	×
EXAMPLE 32	2	3. 6	○	○	○	○
EXAMPLE 33	8	3. 6	○	○	○	○
EXAMPLE 34	10	3. 6	×	○	○	○

80°C200hr



Fig. 9

	Ge [at.%]	Sb/Te	1 X		1 X		2 X		2 X	
			JITTER <12.5%	RECORDING SENSITIVITY <6.0mW	JITTER <12.5%	RECORDING SENSITIVITY <6.0mW	JITTER <12.5%	RECORDING SENSITIVITY <6.0mW	JITTER <12.5%	RECORDING SENSITIVITY <6.0mW
EXAMPLE 35	4	3.7	○	○	○	○	×	○	○	-
EXAMPLE 36	4	4	○	○	○	○	×	○	○	-
EXAMPLE 37	4	4.2	○	○	○	○	○	○	○	-
EXAMPLE 38	4	4.4	○	○	○	○	○	○	○	-
EXAMPLE 39	4	4.8	○	○	○	○	○	○	○	-
EXAMPLE 40	4	5	×	×	×	×	○	×	×	-
EXAMPLE 41	0	4.2	○	○	○	○	○	○	○	×
EXAMPLE 42	2	4.2	○	○	○	○	○	○	○	○
EXAMPLE 43	8	4.2	○	○	○	○	○	○	○	○
EXAMPLE 44	10	4.2	○	○	○	○	×	○	○	○

80°C200hr

Fig. 10

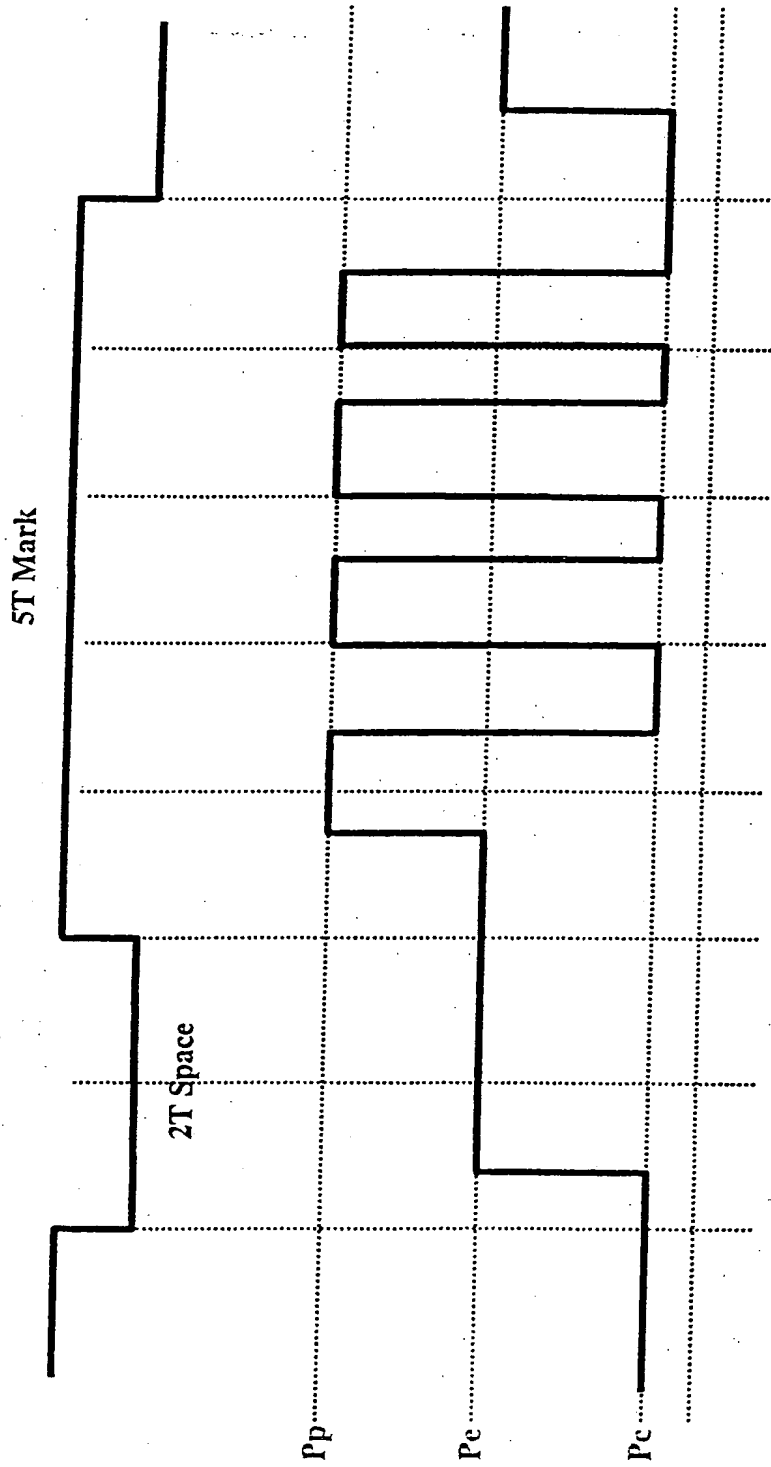


Fig. 11

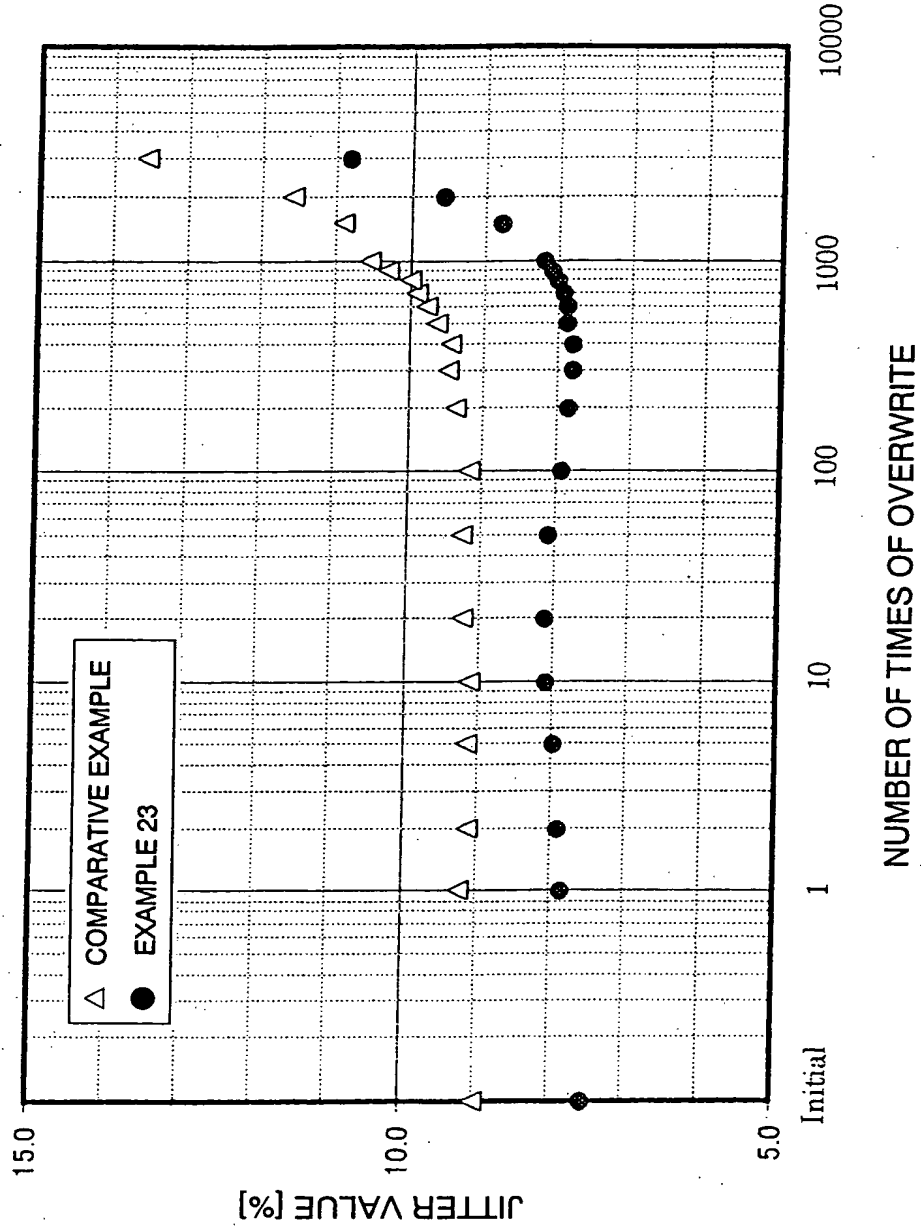
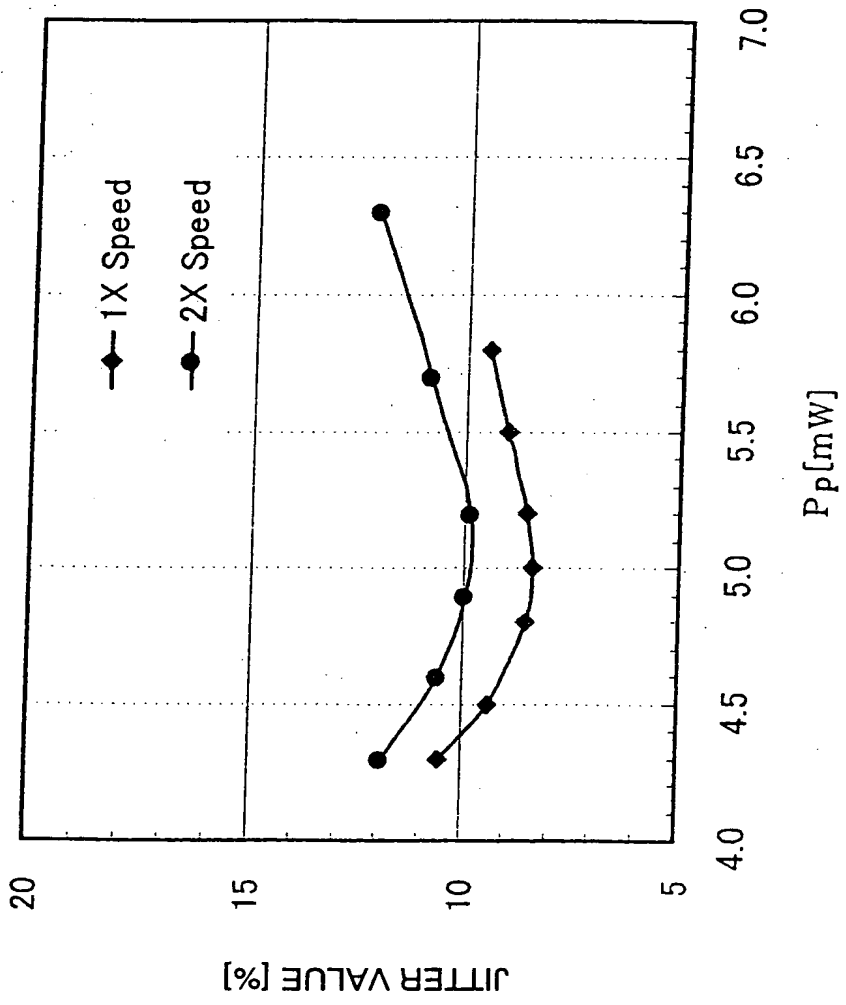
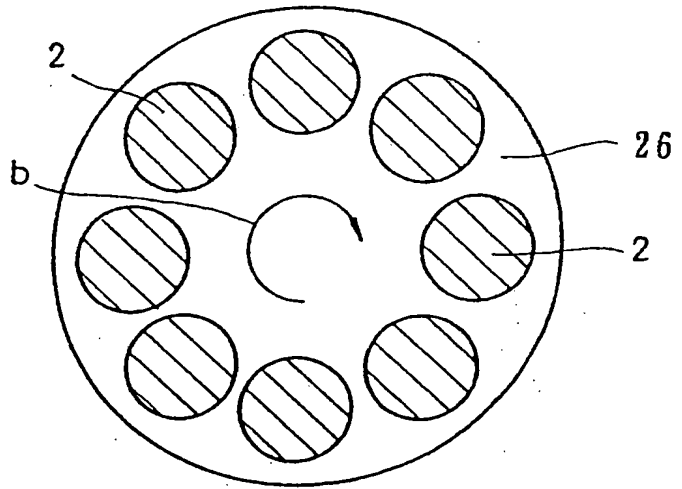


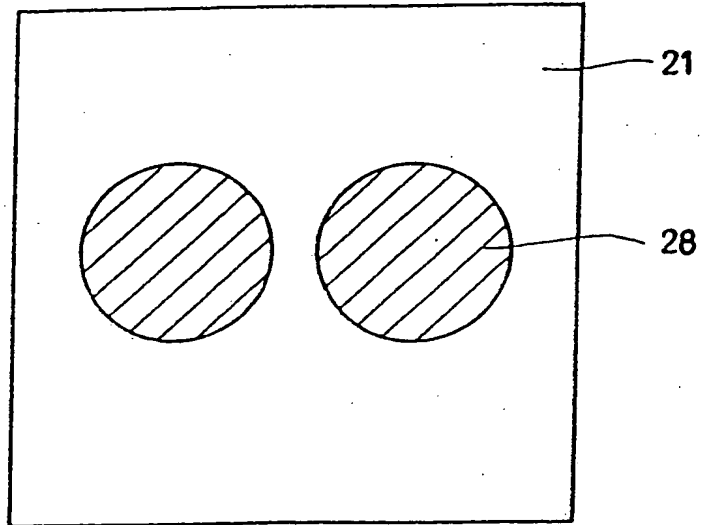
Fig. 12



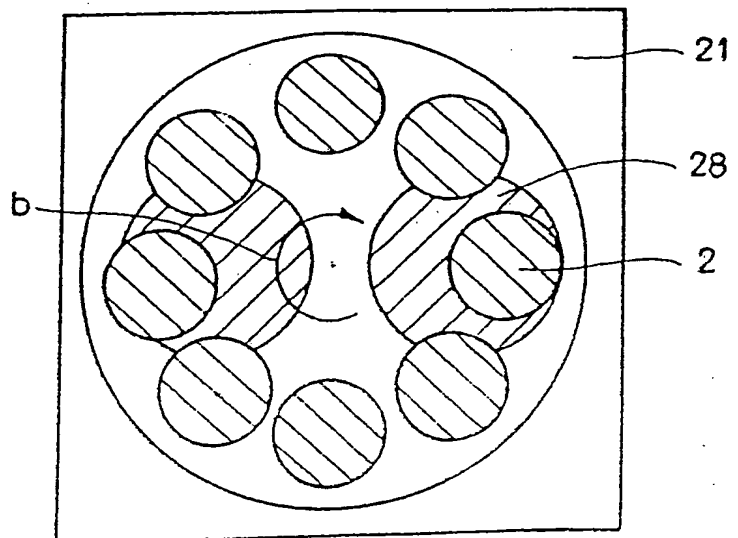
**Fig. 13A**



**Fig. 13B**



**Fig. 13C**



**Fig. 14**

